TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC7SA05F,TC7SA05FU

Inverter (Open Drain)

#### **Features**

• Low voltage operation: V<sub>CC</sub> = 1.8~3.6 V

• High speed operation :  $t_{pz}$  = 3.5 ns (max) ( $V_{CC}$  = 3.0~3.6 V)

:  $t_{pz}$  = 4.1 ns (max) ( $V_{CC}$  = 2.3~2.7 V)

:  $t_{pz}$  = 8.2 ns (max) ( $V_{CC}$  = 1.8 V)

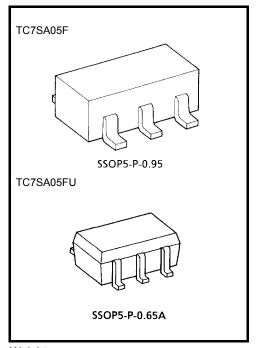
• High Output current : I<sub>OH</sub>/I<sub>OL</sub> = ±24 mA (min) (V<sub>CC</sub> = 3.0 V)

:  $I_{OH}/I_{OL}$  = ±18 mA (min) ( $V_{CC}$  = 2.3 V)

 $: I_{OH}/I_{OL} = \pm 6 \text{ mA (min) (V}_{CC} = 1.8 \text{ V)}$ 

• 3.6-V tolerant input.

• 3.6-V power down protection output.



Weight

SSOP5-P-0.95 : 0.016 g (typ.) SSOP5-P-0.65A : 0.006 g (typ.)

### Absolute Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Power supply voltage	V <sub>CC</sub>	-0.5~4.6	V
DC input voltage	V <sub>IN</sub>	-0.5~4.6	V
DC output voltage	V <sub>OUT</sub>	−0.5~4.6 (Note 1)	٧
Input diode current	l <sub>IK</sub>	-50	mA
Output diode current	I <sub>OK</sub>	−50 (Note 2)	mA
DC output current	lout	±50	mA
Power dissipation	P <sub>D</sub>	200	mW
DC V <sub>CC</sub> /ground current	I <sub>CC</sub>	±100	mA
Storage temperature range	T <sub>stg</sub>	-65~150	°C

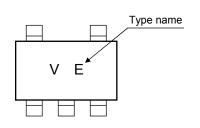
Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

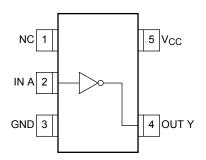
Note 1: IOUT absolute maximum rating must be observed.

Note 2: VOUT < GND

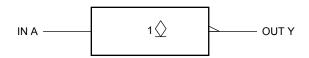
### Marking



# Pin Assignment (top view)



# **Logic Diagram**



### **Truth Table**

Α	Y
L	Z
Н	L

Z: High impedance

# **Operating Ranges**

Characteristics	Symbol	Rating	Unit
Dower aupply voltage	Vaa	1.8~3.6	V
Power supply voltage	V <sub>CC</sub>	1.2~3.6 (Note 3)	V
Input voltage	V <sub>IN</sub>	-0.3~3.6	V
Output voltage	V <sub>OUT</sub>	0~V <sub>CC</sub>	V
		24 (Note 4)	
Output current	I <sub>OH</sub> /I <sub>OL</sub>	18 (Note 5)	mA
		6 (Note 6)	
Operating temperature range	T <sub>opr</sub>	<b>−40~85</b>	°C
Input rise and fall time	dt/dv	0~10 (Note 7)	ns/V

Note 3: Data retention only

Note 4:  $V_{CC} = 3.0 \sim 3.6 \text{ V}$ 

Note 5:  $V_{CC} = 2.3 \sim 2.7 \text{ V}$ 

Note 6:  $V_{CC} = 1.8 \text{ V}$ 

Note 7:  $V_{IN} = 0.8 \sim 2.0 \text{ V}, V_{CC} = 3.0 \text{ V}$ 

### **Electrical Characteristics**

**TOSHIBA** 

# DC Characteristics (Ta = -40~85°C, 2.7 V < V<sub>CC</sub> $\leq$ 3.6 V)

Charac	teristics	Symbol				Min	Max	Unit	
Charac	tensues	Symbol			V <sub>CC</sub> (V)	IVIIII	IVIAX	Offic	
Input voltage	High level	V <sub>IH</sub>		_	2.7~3.6	2.0	_	V	
input voitage	Low level	V <sub>IL</sub>		_	2.7~3.6	_	8.0	V	
				$I_{OL} = 100 \mu A$	2.7~3.6	_	0.2		
Output voltage	Low level	V <sub>OL</sub>	$V_{OL}$ $V_{IN} = V_{IH}$	V <sub>IN</sub> = V <sub>IH</sub>	I <sub>OL</sub> = 12 mA	2.7	_	0.4	V
Output voitage	Low level				VIN — VIH	I <sub>OL</sub> = 18 mA	3.0	_	0.4
				I <sub>OL</sub> = 24 mA	3.0	_	0.55		
Input leakage curre	ent	I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		2.7~3.6	_	±5.0	μА	
Power off leakage	er off leakage current I <sub>OFF</sub>		V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	_	10.0	μА	
Quincoant aumply aurrent		laa	V <sub>IN</sub> = V <sub>CC</sub> or GND		2.7~3.6	_	20.0		
Quiescent supply of	unent	Icc	$V_{CC} \le (V_{IN}, V_{OUT}) \le 3.6 \text{ V}$		2.7~3.6	_	±20.0	μΑ	
Increase in I <sub>CC</sub> per	· input	Δl <sub>CC</sub>	$V_{IH} = V_{CC} - 0.6$	V	2.7~3.6		750		

# DC Characteristics (Ta = $-40~85^{\circ}$ C, 2.3 V $\leq$ V<sub>CC</sub> $\leq$ 2.7 V)

Characteristics Symbol Test Condition		condition		Min	Max	Unit		
Charac	teristics	Symbol	rest	ondition	V <sub>CC</sub> (V)	IVIIII	IVIAX	Offic
Input voltage	High level	V <sub>IH</sub>	-	_	2.3~2.7	1.6	_	V
input voltage	Low level	V <sub>IL</sub>	_		2.3~2.7	_	0.7	V
				$I_{OL} = 100 \mu A$	2.3~2.7	_	0.2	
Output voltage	Low level	$V_{OL}$	$V_{IN} = V_{IH}$	I <sub>OL</sub> = 12 mA	2.3	_	0.4	V
				I <sub>OL</sub> = 18 mA	2.3	_	0.6	
Input leakage curre	ent	I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		2.3~2.7	_	±5.0	μΑ
Power off leakage	current	l <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	_	10.0	μΑ
Quiescent supply current		loo	V <sub>IN</sub> = V <sub>CC</sub> or GND		2.3~2.7	_	20.0	^
Quiescerit supply o	unent	Icc	V <sub>CC</sub> ≤ (V <sub>IN</sub> , V <sub>OUT</sub>	-) ≦ 3.6 V	2.3~2.7	_	±20.0	μА

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# DC Characteristics (Ta = $-40\sim85^{\circ}$ C, 1.8 V $\leq$ V<sub>CC</sub> < 2.3 V)

Charac	teristics	Symbol	Test Condition		V <sub>CC</sub> (V)	Min	Max	Unit	
Input voltage	High level	V <sub>IH</sub>	-	_		0.7 × V <sub>CC</sub>	_	V	
Input voltage	Low level	V <sub>IL</sub>	-	_		_	0.2 × V <sub>CC</sub>	V	
Output valtage	Low level	.,	V <sub>OI</sub> V <sub>IN</sub> = V <sub>IH</sub>	$I_{OL} = 100 \mu A$	$I_{OL} = 100 \mu A$	1.8	_	0.2	V
Output voltage	Low level	V <sub>OL</sub>	VIN – VIH	I <sub>OL</sub> = 6 mA	1.8	_	0.3	V	
Input leakage curre	ent	I <sub>IN</sub>	V <sub>IN</sub> = 0~3.6 V		1.8	_	±5.0	μА	
Power off leakage	current	l <sub>OFF</sub>	V <sub>IN</sub> , V <sub>OUT</sub> = 0~3.6 V		0	_	10.0	μА	
Quiescent supply current		loo	V <sub>IN</sub> = V <sub>CC</sub> or GND		1.8	_	20.0		
Quiescent supply o	unent	Icc	V <sub>CC</sub> ≦ (V <sub>IN</sub> , V <sub>OUT</sub>	-) ≦ 3.6 V	1.8	_	±20.0	μΑ	

### AC Characteristics (Ta = -40~85°C, input: $t_r = t_f = 2.0$ ns, $C_L = 30$ pF, $R_L = 500$ $\Omega$ )

Characteristics	Symbol	Test Condition	V <sub>CC</sub> (V)	Min	Max	Unit
			1.8	1.0	8.2	
	t <sub>pZL</sub>	Figure 1, Figure 2	$2.5\pm0.2$	8.0	4.1	ns
Propagation delay time				0.6	3.5	
Tropagation delay time		t <sub>pLZ</sub> Figure 1, Figure 2	1.8	1.0	6.8	
	t <sub>pLZ</sub>		$2.5 \pm 0.2$	8.0	3.8	ns
			$3.3 \pm 0.3$	0.6	3.5	

For  $C_L = 50\ pF$ , add approximately 300 ps to the AC maximum specification.

### **Capacitive Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition			Tun	Unit	
Characteristics	Syllibol			V <sub>CC</sub> (V)	Тур.	Ullit	
Input capacitance	C <sub>IN</sub>		_		1.8, 2.5, 3.3	4	pF
Output capacitance	C <sub>OUT</sub>		_			3	pF
Power dissipation capacitance	C <sub>PD</sub>	f <sub>IN</sub> = 10 MHz		(Note 8)	1.8, 2.5, 3.3	4	pF

Note 8: C<sub>PD</sub> is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation.

 $I_{CC (opr.)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$ 

### **AC Test Circuit**

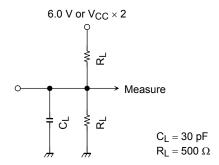
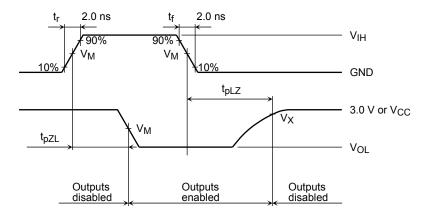


Figure 1

### **AC Waveforms**

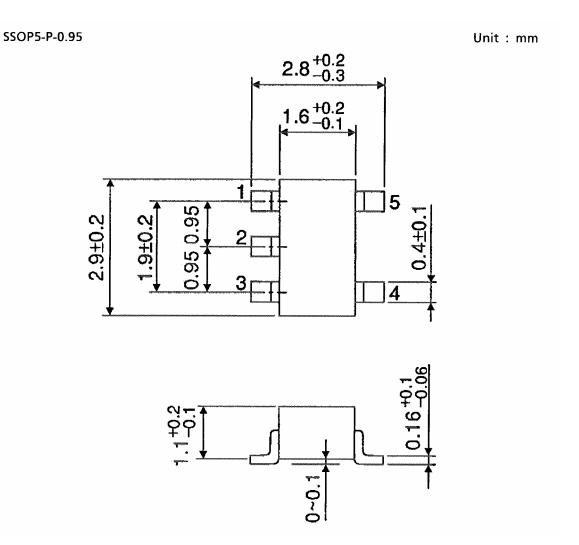


Symbol		$V_{CC}$	
Symbol	$3.3\pm0.3~\textrm{V}$	$2.5\pm0.2~\textrm{V}$	1.8 V
$V_{IH}$	2.7 V	V <sub>CC</sub>	V <sub>CC</sub>
$V_{M}$	1.5 V	V <sub>CC</sub> /2	V <sub>CC</sub> /2
VX	V <sub>OH</sub> – 0.3 V	V <sub>OH</sub> – 0.15 V	V <sub>OH</sub> – 0.15 V

Figure 2 t<sub>pZL</sub>, t<sub>pLZ</sub>

# **Package Dimensions**

**TOSHIBA** 



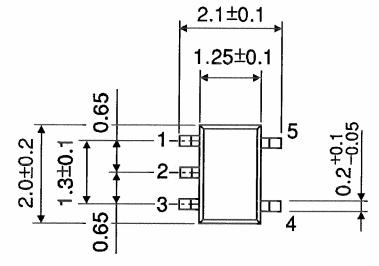
Weight: 0.016 g (typ.)

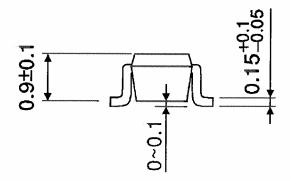
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# **Package Dimensions**

SSOP5-P-0.65A Unit: mm





Weight: 0.006 g (typ.)

TC7SA05F/FU

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20070701-EN GENERAL

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